


<b>Search Notes</b>  	<b>Application/Control No.</b>  10583716	<b>Applicant(s)/Patent Under Reexamination</b>  WATANABE ET AL.
	<b>Examiner</b>  Pablo N Tran	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	572,, 343.1,, 571, 573, 574, 333, 343.2, 343.5, 343.6, 550.1, 571, 575.1, 90.3, 127.1, 127.5, 128, 129	10/25/08	PT
323	268-273	10/25/08	PT

SEARCH NOTES		
Search Notes	Date	Examiner
East/West	10/25/08	PT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
455	343.1, 127.1	10/25/08	PT

	/P. N. T./ Primary Examiner.Art Unit 2618
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